RECAP LECTURE 4

THERMAL LIMIT OF STOCHASTIC RADIATION PROCESSES $h\nu << kT$ Thermal limit $\overline{\Delta P^2}(\nu) = \bar{P}^2(\nu)$

USE INCOMPLETE GAMMA FUNCTION TO CALCULATE POISSON AND GAUSS CUMULATIVE DISTRIBUTION FUNCTION

PROPAGATION OF ERRORS UNDER THE ASSUMPTION OF INDEPENDENT VARIABLES

$$\begin{split} \bar{f} &= f(\bar{u},\bar{v},..) \\ \sigma_f^2 &= \sigma_u^2 (\frac{\partial f}{\partial u})^2 + \sigma_v^2 (\frac{\partial f}{\partial v})^2 + \ldots \end{split}$$

TODAY:

COMPARING DATA WITH A MODEL: LEAST-SQUARES FITTING, MAXIMUM LIKELIHOOD METHOD: GAUSSIAN DATA

MONTE CARLO SIMULATIONS

"REAL" MAXIMUM LIKELIHOOD METHOD: POISSONIAN DATA

OAF2 CHAPTER 5.3+5.4 SEE ALSO NUM RES CHAPTER 15

COMPARE DATA WITH A MODEL

DESCRIBE DATA IN TERMS OF A CONTINUOUS FUNCTION

COMPARE OBSERVATIONS (DATA) WITH THEORETICAL MODEL PREDICTION

DESCRIBE THE DATA IN A FEW PARAMETERS

EXAMPLE: CONTINUOUS MODEL THROUGH DISCRETE



X-RAY BINARY IN QUIESCENCE NEUTRON STAR ATMOSPHERE MODEL

MAXIMUM LIKELIHOOD: MOST LIKELY OUTCOME IS ASSUMED TO BE THE 'CORRECT' ONE <u>METHOD OF LEAST SQUARES</u> $dQ_i = P_i dx$ PROBABILITY DENSITY FUNCTION $\frac{dQ_i}{dx} = P_i$ \hookrightarrow GAUSS, POISSON

$$P(y_i)\Delta y = \frac{1}{\sqrt{2\pi\sigma_i}} exp(-\frac{1}{2}\frac{(y_i - y_m)^2}{\sigma_i^2})\Delta y$$

NOTE: y_m = MODEL VALUE NOT MEAN HERE!

METHOD OF LEAST SQUARES $P \propto \prod^{n} \{exp[-\frac{1}{2}(\frac{y_i - y_m}{\sigma_i})^2]\}$ i=1 $\propto exp[-\frac{1}{2}\sum_{i=1}^{N}(\frac{y_i-y_m}{\sigma_i})^2]\}$ MINIMISE: $\chi^2 \equiv \sum_{i=1}^N (rac{y_i - y_m}{\sigma_i})^2$

MINIMISATION: ROOT FINDING PROBLEM

1 D:
$$\frac{\partial}{\partial y_m} \sum_{i=1}^N (\frac{y_i - y_m}{\sigma_i})^2 = 0$$

More about χ^2

DRAWN FROM NORMAL DISTRIBUTION

DISTRIBUTION OF χ^2_i IS A χ^2 DISTRIBUTION

FOR N MEASUREMENTS DESCRIBED BY M VARIABLES, THERE ARE N-M DEGREES OF FREEDOM (D.O.F.)

PROBABILITY OF OBTAINING A χ^2 as *bad* as observed observed

$$P(\chi^2_{obs}) = \text{gammq}(\frac{N-M}{2}, \frac{\chi^2_{obs}}{2})$$



BEST-FITTING PARAMETERS

AN ERROR ESTIMATE OF THE UNCERTAINTY OF THE FITTED PARAMETERS

A PROBABILITY THAT THE DATA IS DRAWN FROM A PARENT POPULATION DESCRIBED BY THE MODEL PARAMETERS NOTE THAT OUTLIERS MAKE THIS PROBABILITY GENERALLY LOW

BE AWARE OF NON-GAUSSIAN DISTRIBUTIONS



PART OF U-BAND IMAGE VLT



REMOVE OUTLIERS VIA (SIGMA) CLIPPING

SINUSOID: CHI**2=81.2 FOR 26 DEGREES OF



SINUSOID: CHI**2=580 FOR 28 DEGREES OF



SINUSOID: CHI**2=12 FOR 27 DEGREES OF



 χ^2 surface



not always this smooth!

Think about what to fit!

$$y(x) = ae^{bx+c}$$
 a and c are degenerate

$$y(x) = ae^{-bx}$$
 is equal to $\log[y(x)] = c - bx$

which is linear in fitting *c* and *b* but the errors are no longer Gaussian

E.g. computer exercise 3

CHANDRA CCD (ACIS) OBSERVATION OF AN X-RAY BINARY



SAME DATA AS BEFORE



VALUE AND POISSON ERRORS



EXAMPLE FROM BEVINGTON & ROBERTSON 1992

FITTING A STRAIGHT LINE TO THE DATA

 $y_m(x_i,a,b) = a + b x_i$ minimise χ_i^2 to find best-fitting parameters



DETERMINE ERRORS ON THE BEST-FITTING PARAMETERS

Remember
$$\sigma_f^2 = \sigma_u^2 (\frac{\partial f}{\partial u})^2 + \sigma_v^2 (\frac{\partial f}{\partial v})^2 + \dots$$

$$\sigma_a^2 = \sum_{i=1}^{n} [\sigma_i^2 \frac{\partial a}{\partial y_i}]^2$$

 $\partial u\,\&\,\partial v$ etc are the different measurement values y_i



FINALLY CALCULATE THE PROBABILITY
OF OBTAINING THE
$$\chi^2$$

BY CHANCE
 $P(\chi^2_{obs}) = \text{gammq}(\frac{N-M}{2}, \frac{\chi^2_{obs}}{2})$
FOR THE STRAIGHT LINE FIT M=2
 $\nu = N - M$ DEGREES OF FREEDOM
REDUCED χ^2_{ν}
 $\chi^2_{\nu} \equiv \frac{\chi^2}{\nu}$
FOR DATA FITTING: $\chi^2_{\nu} \sim 1$ $\chi^2 \approx \nu$
 $\sigma_{\chi^2} = \sqrt{2\nu}$

VALUE AND POISSON ERRORS



EXAMPLE FROM BEVINGTON & ROBERTSON 1992

ESTIMATING CONFIDENCE REGIONS VIA MONTE CARLO

MONTE CARLO SIMULATIONS

1 REPLACE THE OBSERVED VALUES BY ANOTHER RANDOM SELECTED VALUE FROM THE RANGE Y+-SIGMA

2 REPEAT FITTING (CHI**2 MINIMISATION ETC)

3 REPEAT 1 & 2 N TIMES TO BUILD UP A DISTRIBUTION IN THE DETERMINED PARAMETERS AND FROM THAT DETERMINE THE MEAN, VARIANCE ETC

ESTIMATING CONFIDENCE LIMITS

MONTE CARLO SIMULATIONS



ASSUME THAT THE DISTRIBUTION OF

 $a_{i} - a_{0}$

IS CLOSE TO THE PROBABILITY DISTRIBUTION

$$a_i - a_{true}$$

$a_i - a_0$ distribution we can determine via Monte Carlo simulations

MANY MONTE CARLO METHODS

BASIS: (PSEUDO) RANDOM DRAWS

Also simulate an experiment! a.o. useful for proposal writing Computer exercise

MONTE CARLO SIMULATIONS



CALCULATE DISTRIBUTION OF $a_i - a_0$

BY SIMULATING MANY SETS OF DATA AND USING $\chi^2_{\rm FITTING}$ to determine a_i

SPECIAL MC: BOOTSTRAPPING

1 REPLACE A RANDOM NUMBER OF OBSERVED VALUES BY ANOTHER RANDOM SELECTED OBSERVED VALUE

2 REPEAT FITTING (CHI**2 MINIMISATION ETC)

3 REPEAT 1 & 2 N TIMES TO BUILD UP A DISTRIBUTION IN THE DETERMINED PARAMETERS AND FROM THAT DETERMINE THE MEAN, VARIANCE ETC

BOOTSTRAP METHOD AND APPLICATION

X-RAY BINARY V395 CAR





BROADENING AND OPTIMAL SUBTRACTION



BOOTSTRAP METHOD: AN APPLICATION



CONFIDENCE LIMITS

SINGLE VS. MULTIPLE PARAMETER CONFIDENCE REGION



FROM NUM RES PAGE 688

PROJECTIONS



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$$\begin{array}{ll} \mbox{Maximum likelihood method} \\ \mbox{(Poisson noise, unbinned data)} \\ \mbox{Probability to find } n_i \mbox{photons when} \\ m_i \mbox{Expected} \\ \mbox{for each pixel i in an image} & P_i = \frac{m_i^{n_i} e^{-m_i}}{n_i!} \\ \mbox{for each pixel i in an image} & P_i = \frac{m_i^{n_i} e^{-m_i}}{n_i!} \\ \mbox{total probability} & L' \equiv \prod_i P_i \\ \mbox{in $n_i = \sum_i \ln P_i = \sum_i n_i \ln m_i - \sum_i m_i - \sum_i \ln n_i!} \\ \mbox{minimise} & \ln L \equiv -2(\sum_i n_i \ln m_i - \sum_i m_i) \end{array}$$

DETECTION OF A CONSTANT BACKGROUND, A, PLUS A SOURCE OF STRENGTH B OF WHICH A FRACTION f_i FALLS ON PIXEL i

$$-0.5\ln L = \sum_{i} n_i \ln(A + Bf_i) - \sum_{i} (A + Bf_i)$$

AGAIN SEARCH FOR THE MINIMUM OF L FOR VARIATIONS IN A AND B

DETERMINED INDEPENDENTLY IN SOME CASES TOTAL PIXELS Z

$$\frac{\partial \ln L}{\partial A} = 0 \Rightarrow \sum_{i} \frac{n_i}{A + Bf_i} - \sum_{i} (1) = \sum_{i} \frac{n_i}{A + Bf_i} - Z = 0$$
$$\frac{\partial \ln L}{\partial B} = 0 \Rightarrow \sum_{i} \frac{n_i f_i}{A + Bf_i} - \sum_{i} (f_i) = \sum_{i} \frac{n_i f_i}{A + Bf_i} - 1 = 0$$

MAXIMUM LIKELIHOOD METHOD (APPLICATION X-RAY BINARY CIR X-1, A JET PRESENT?)



CHANDRA HRC OBSERVATION

MODEL AND SUBSEQUENTLY SUBTRACT PSF

ONLY CLOSE TO THE SOURCE THE ASSUMPTION OF A CONSTANT BACKGROUND

IS VALID

APPLICATION MAXIMUM LIKELIHOOD METHOD X-RAY BINARY CIR X-1



ONE SOURCE SUBTRACTED